

Notice of References Cited	Application/Control No. 10/572,589		Applicant(s)/Patent Under Reexamination YAMAUCHI ET AL.	
	Examiner SHIN-HON CHEN		Art Unit 2431	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0100755	05-2007	Kragt et al.	705/051
*	B	US-7,093,296	08-2006	Nusser et al.	726/26
*	C	US-2002/0120577	08-2002	Hans et al.	705/59
*	D	US-2005/0177516	08-2005	Vandewater et al.	705/057
*	E	US-2003/0078853	04-2003	Peinado et al.	705/26
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.